

Dual Modulus Prescaler

These devices are two-modulus prescalers which will divide by 5 and 6, 8 and 9, and 10 and 11, respectively. A MECL-to-MTTL translator is provided to interface directly with the MC12014 Counter Control Logic. In addition, there is a buffered clock input and MECL bias voltage source.

- MC12009 480 MHz (÷ 5/6), MC12011 550 MHz (÷ 8/9), MC12013 550 MHz (÷ 10/11)
- MECL to MTTL Translator on Chip
- MECL and MTTL Enable Inputs
- 5.0 or -5.2 V Operation*
- Buffered Clock Input Series Input RC Typ, 20 Ohms and 4 pF
- VBB Reference Voltage
- 310 Milliwatts (Typ)
 - * When using a 5.0 V supply, apply 5.0 V to Pin 1 (V_{CCO}), Pin 6 (MTTL V_{CC}), Pin 16 (V_{CC}), and ground Pin 8 (V_{EE}). When using –5.2 V supply, ground Pin 1 (V_{CCO}), Pin 6 (MTTL V_{CC}), and Pin 16 (V_{CC}) and apply–5.2 V to Pin 8 (V_{EE}). If the translator is not required, Pin 6 may be left open to conserve dc power drain.



SEMICONDUCTOR TECHNICAL DATA



P SUFFIX PLASTIC PACKAGE CASE 648



MAXIMUM RATINGS

Characteristic	Symbol	Rating	Unit
(Ratings above which device life ma	ay be impaired	(k	
Power Supply Voltage (V _{CC} = 0)	VEE	-8.0	Vdc
Input Voltage (V _{CC} = 0)	V _{in}	0 to V _{EE}	Vdc
Output Source Current Continuous Surge	lO	< 50 < 100	mAdc
Storage Temperature Range	T _{stg}	-65 to +175	°C

(Recommended Maximum Ratings above which performance may be degraded)

Operating Temperature Range MC12009, MC12011, MC12013	Т _А	-30 to +85	°C
DC Fan–Out (Note 1) (Gates and Flip–Flops)	n	70	—

NOTES: 1. AC fan–out is limited by desired system performance. 2. ESD data available upon request.

ORDERING INFORMATION

Device	Operating Temperature Range	Package
MC12009P		
MC12011P	$T_A = -35^\circ$ to +85°C	Plastic
MC12013P		







ELECTRICAL CHARACTERISTICS (Supply Voltage = -5.2 V, unless otherwise noted.)
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			Test Limits							
		Pin Under	-3	D∘C	+2	5°C	+8	5°C		
Characteristic	Symbol	Test	Min	Max	Min	Max	Min	Max	Unit	
Power Supply Drain Current	ICC1	8	-88		-80		-80		mAdo	
	ICC2	6		5.2		5.2		5.2	mAdo	
Input Current	linH1	15 11 12 13		375 375 375 375		250 250 250 250		250 250 250 250	μAdo	
	linH2	4 5	1.7 1.7	6.0 6.0	2.0 2.0	6.0 6.0	2.0 2.0	6.4 6.4	mAdc	
	linH3	5	0.7	3.0	1.0	3.0	1.0	3.6		
	linH4	9 10		100 100		100 100		100 100	μAdc	
Leakage Current	linL1	15 11 12 13	-10 -10 -10 -10		-10 -10 -10 -10		-10 -10 -10 -10		μAdc	
	l _{inL2}	9 10	-1.6 -1.6		-1.6 -1.6		-1.6 -1.6		mAdd	
Reference Voltage	V _{BB}	14			-1.360	-1.160			Vdc	
Logic '1' Output Voltage	V _{OH1} (Note 1)	2 3	-1.100 -1.100	-0.890 -0.890	-1.000 -1.000	-0.810 -0.810	-0.930 -0.930	-0.700 -0.700	Vdc	
	VOH2	7	-2.8		-2.6		-2.4			
Logic '0' Output Voltage	VOL1 (Note 1)	2 3	-1.990 -1.990	-1.675 -1.675	-1.950 -1.950	-1.650 -1.650	-1.925 -1.925	-1.615 -1.615	Vdc	
	V _{OL2}	7		-4.26		-4.40		-4.48		
Logic '1' Threshold Voltage	VOHA (Note 2)	2 3	-1.120 -1.120		-1.020 -1.020		-0.950 -0.950		Vdc	
Logic '0' Threshold Voltage	V _{OLA} (Note 3)	2 3		-1.655 -1.655		-1.630 -1.630		-1.595 -1.595	Vdc	
Short Circuit Current	los	7	-65	-20	-65	-20	-65	-20	mAdd	

1. Test outputs of the device must be tested by sequencing through the truth table. All input, power supply and ground voltages must be maintained between tests. The clock input is the waveform shown.

2. In addition to meeting the output levels specified, the device must divide by 5, 8 or 10 during this test. The clock input is the waveform shown.

3. In addition to meeting the output levels specified, the device must divide by 6, 9 or 11 during this test. The clock input is the waveform shown.

Each MECL 10,000 series circuit has been designed to meet the dc specifications shown in the test table, after thermal equilibrium has been established. The circuit is in a test socket or mounted on a printed circuit board and transverse air flow greater than 500 linear fpm is maintained. Outputs are terminated through a 50 Ω resistor to -2.0 V. Test procedures are shown for only one gate. The other gates are tested in the same manner.

VIHmax

VILmin

				TEST V	OLTAGE/CU	JRRENT VAL	UES		
					Volt	S			
	@ Test Temp	perature	VIHmax	V _{ILmin}	VIHAmin	V _{ILAmax}	VIH	VILH	
		–30°C	-0.890	-1.990	-1.205	-1.500	-2.8	-4.7	
		+25°C	-0.810	-1.950	-1.105	-1.475	-2.8	-4.7	
		+85°C	-0.700	-1.925	-1.035	-1.440	-2.8	-4.7	
		Pin	TEST VOLTAGE APPLIED TO PINS LISTED BELOW					w	
Characteristic	Symbol	Under Test	V _{IHmax}	v _{ILmin}	VIHAmin	V _{ILAmax}	VIH	VIL	Gnd
Power Supply Drain Current	ICC1	8							1,16
	ICC2	6	4	5					6
Input Current	linH1	15 11 12 13	15 11 12 13						1,16 1,16 1,16 1,16
	linH2	4 5	5 5	4 4					6 6
	linH3	5	4	5					6
	linH4	9 10					9 10		1,16 1,16
Leakage Current	linL1	15 11 12 13							1,16 1,16 1,16 1,16 1,16
	linL2	9 10						9 10	1,16 1,16
Reference Voltage	V _{BB}	14							1,16
Logic '1' Output Voltage	VOH1 (Note 1.)	2 3		11,12,13 11,12,13				9,10 9,10	1,16 1,16
	VOH2	7	5	4					6
Logic '0' Output Voltage	VOL1 (Note 1.)	2 3		11,12,13 11,12,13				9,10 9,10	1,16 1,16
	V _{OL2}	7	4	5					6
Logic '1' Threshold Voltage	V _{OHA} (Note 2.)	2 3			11,12,13 11,12,13				1,16 1,16
Logic '0' Threshold Voltage	V _{OLA} (Note 3.)	2 3				11,12,13 11,12,13			1,16 1,16
Short Circuit Current	IOS	7	5	4				7	6

 Test outputs of the device must be tested by sequencing through the truth table. All input, power supply and ground voltages must be maintained between tests. The clock input is the waveform shown.
 In addition to meeting the output levels specified, the device must divide by 5, 8 or 10 during this test. The clock

Clock Input

VIHmax

input is the waveform shown.In addition to meeting the output levels specified, the device must divide by 6, 9 or 11 during this test. The clock input is the waveform shown.

ELECTRICAL CHARACTERISTICS (S	pply Voltage = -5.2 V, unless otherwise noted.) (continued)
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				TEST V	OLTAGE/CU	JRRENT VA	LUES		
				Volts			mA]
	@ Test Temperature		VIHT	VILT	VEE	١L	IOL	ЮН	
		–30°C	-3.2	-4.4	-5.2	-0.25	16	-0.40	
		+25°C	-3.2	-4.4	-5.2	-0.25	16	-0.40	
		+85°C	-3.2	-4.4	-5.2	-0.25	16	-0.40	
		Pin	TE	ST VOLTAGE	APPLIED	TO PINS LIS		wc	
Characteristic	Symbol	Under Test	VIHT	V _{ILT}	VEE	١L	IOL	ЮН	Gnd
Power Supply Drain Current	ICC1	8			8				1,16
	ICC2	6			8				6
Input Current	linH1	15 11 12 13	9,10 9,10 9,10		8 8 8 8				1,16 1,16 1,16 1,16
	linH2	4 5			8 8				6 6
	linH3	5			8				6
	linH4	9 10			8 8				1,16 1,16
Leakage Current	l _{inL1}	15 11 12 13			8,15 8,11 8,12 8,13				1,16 1,16 1,16 1,16 1,16
	linL2	9 10			8 8				1,16 1,16
Reference Voltage	V _{BB}	14			8	14			1,16
Logic '1' Output Voltage	VOH1 (Note 1.)	2 3			8 8				1,16 1,16
	V _{OH2}	7			8			7	6
Logic '0' Output Voltage	VOL1 (Note 1.)	2 3			8 8				1,16 1,16
	V _{OL2}	7			8		7		6
Logic '1' Threshold Voltage	VOHA (Note 2.)	2 3	9,10 9,10		8 8				1,16 1,16
Logic '0' Threshold Voltage	V _{OLA} (Note 3.)	2 3		9,10 9,10	8 8				1,16 1,16
Short Circuit Current	IOS	7			8				6

1. Test outputs of the device must be tested by sequencing through the truth table. All input, power supply and ground voltages must be maintained between tests. The clock input is the waveform shown.

Clock Input

VIHmax

VILmin

2. In addition to meeting the output levels specified, the device must divide by 5, 8 or 10 during this test. The clock input is the waveform shown.3. In addition to meeting the output levels specified, the device must divide by 6, 9 or 11 during this test. The clock

input is the waveform shown.

			Test Limits						
		Pin Under	-3	0°C	+2	5°C	+8	5°C	1
Characteristic	Symbol	Test	Min	Max	Min	Max	Min	Max	Unit
Power Supply Drain Current	ICC1	8	-88		-80		-80		mAdo
	ICC2	6		5.2		5.2		5.2	mAdo
Input Current	linH1	15 11 12 13		375 375 375 375 375		250 250 250 250		250 250 250 250	μAdo
	linH2	4 5	1.7 1.7	6.0 6.0	2.0 2.0	6.0 6.0	2.0 2.0	6.4 6.4	mAdc
	linH3	5	0.7	3.0	1.0	3.0	1.0	3.6	
	linH4	9 10			100 100	100 100		100 100	μAdc
Leakage Current	linL1	15 11 12 13	-10 -10 -10 -10		-10 -10 -10 -10		-10 -10 -10 -10		μAdc
	linL2	9 10	-1.6 -1.6		-1.6 -1.6		-1.6 -1.6		mAdo
Reference Voltage	V _{BB}	14			3.67	3.87			Vdc
Logic '1' Output Voltage	V _{OH1} (Note 4.)	2 3	3.900 3.900	4.110 4.110	4.000 4.000	4.190 4.190	4.070 4.070	4.300 4.300	Vdc
	VOH2	7	2.4		2.6		2.8		
Logic '0' Output Voltage	VOL1 (Note 4.)	2 3	3.070 3.070	3.385 3.385	3.110 3.110	3.410 3.410	3.135 3.135	3.445 3.445	Vdc
	V _{OL2}	7		0.94		0.80		0.72	
Logic '1' Threshold Voltage	V _{OHA} (Note 5.)	2 3	3.880 3.880		3.980 3.980		4.050 4.050		Vdc
Logic '0' Threshold Voltage	V _{OLA} (Note 6.)	2 3		3.405 3.405		3.430 3.430		3.465 3.465	Vdc
Short Circuit Current	los	7	-65	-20	-65	-20	-65	-20	mAdo

Test outputs of the device must be tested by sequencing through the truth table. All input, power supply and ground voltages must be maintained between tests. The clock input is the waveform shown.

5. In addition to meeting the output levels specified, the device must divide by 5, 8 or 10 during this test. The clock input is the waveform shown.

6. In addition to meeting the output levels specified, the device must divide by 6, 9 or 11 during this test. The clock input is the waveform shown.

Each MECL 10,000 series circuit has been designed to meet the dc specifications shown in the test table, after thermal equilibrium has been established. The circuit is in a test socket or mounted on a printed circuit board and transverse air flow greater than 500 linear fpm is maintained. Outputs are terminated through a 50 Ω resistor to -2.0 V. Test procedures are shown for only one gate. The other gates are tested in the same manner.

VIHmax

VILmin

ELECTRICAL CHARACTERISTICS (Supply Voltage = 5.0 V, unless otherwise noted.) (continued)

				TEST V	OLTAGE/CU	JRRENT VAL	UES				
			Volts								
	@ Test Temp	perature	V _{IHmax}	VILmin	VIHAmin	V _{ILAmax}	VIH	VILH			
		–30°C	+4.110	+3.070	+3.795	+3.500	+2.4	+0.5			
		+25°C	+4.190	+3.110	+3.895	+3.525	+2.4	+0.5			
		+85°C	+4.300	+3.135	+3.965	+3.560	+2.4	+0.5			
		Pin	TE	ST VOLTAGE	APPLIED	TO PINS LIS	TED BELO	W	1		
Characteristic	Symbol	Under Test	V _{IHmax}	V _{ILmin}	V _{IHAmin}	V _{ILAmax}	VIH	VIL	(V _{EE}) Gnd		
Power Supply Drain Current	ICC1	8							8		
	ICC2	6	4	5					8		
Input Current	linH1	15 11 12 13	15 11 12 13						8 8 8 8		
	linH2	4 5	5 5	4 4					8 8		
	linH3	5	4	5					8		
	linH4	9 10					9 10		8 8		
Leakage Current	linL1	15 11 12 13							8,15 8,11 8,12 8,13		
	linL2	9 10						9 10	8 8		
Reference Voltage	V _{BB}	14							8		
Logic '1' Output Voltage	VOH1 (Note 4.)	2 3		11,12,13 11,12,13				9,10 9,10	8 8		
	V _{OH2}	7	5	4					8		
Logic '0' Output Voltage	VOL1 (Note 4.)	2 3		11,12,13 11,12,13				9,10 9,10	8 8		
	V _{OL2}	7	4	5					8		
Logic '1' Threshold Voltage	VOHA (Note 5.)	2 3			11,12,13 11,12,13				8 8		
Logic '0' Threshold Voltage	VOLA (Note 6.)	2 3				11,12,13 11,12,13			8 8		
Short Circuit Current	IOS	7	5	4				7	8		

4. Test outputs of the device must be tested by sequencing through the truth table. All input, power supply and ground voltages must be maintained between tests. The clock input is the waveform shown.In addition to meeting the output levels specified, the device must divide by 5, 8 or 10 during this test. The clock

Clock Input

VIHmax VILmin

input is the waveform shown.In addition to meeting the output levels specified, the device must divide by 6, 9 or 11 during this test. The clock

input is the waveform shown.

ELECTRICAL CHARACTERISTICS (Supply Voltage = 5.0 V, unless otherwise noted.) (continued)

			TEST VOLTAGE/CURRENT VALUES									
				Volts								
	@ Test Temp	VIHT	VILT	VCC	١L	loL	ЮН					
		–30°C	+2.0	+0.8	+5.0	-0.25	16	-0.40				
		+25°C	+2.0	+0.8	+5.0	-0.25	16	-0.40]			
		+85°C	+2.0	+0.8	+5.0	-0.25	16	-0.40				
		Pin	TEST VOLTAGE APPLIED TO PINS LISTED BELOW									
Characteristic	Symbol	Under Test	VIHT	VILT	Vcc	IL.	IOL	ЮН	(V _{EE} Gno			
Power Supply Drain Current	ICC1	8			1,16				8			
	ICC2	6			6				8			
Input Current	linH1	15 11 12 13	9,10 9,10 9,10		1,16 1,16 1,16 1,16				8 8 8 8			
	linH2	4 5			6 6				8 8			
	l _{inH3}	5			6				8			
	linH4	9 10			1,16 1,16				8 8			
Leakage Current	linL1	15 11 12 13			1,16 1,16 1,16 1,16 1,16				8,15 8,11 8,12 8,13			
	linL2	9 10			1,16 1,16				8 8			
Reference Voltage	V _{BB}	14			1,16	14			8			
Logic '1' Output Voltage	VOH1 (Note 4.)	2 3			1,16 1,16				8 8			
	V _{OH2}	7			6			7	8			
Logic '0' Output Voltage	VOL1 (Note 4.)	2 3			1,16 1,16				8 8			
	V _{OL2}	7			6		7		8			
Logic '1' Threshold Voltage	VOHA (Note 5.)	2 3	9,10 9,10		1,16 1,16				8 8			
Logic '0' Threshold Voltage	V _{OLA} (Note 6.)	2 3		9,10 9,10	1,16 1,16				8 8			
Short Circuit Current	los	7			6				8			

Test outputs of the device must be tested by sequencing through the truth table. All input, power supply and ground voltages must be maintained between tests. The clock input is the waveform shown.
 In addition to meeting the output levels specified, the device must divide by 5, 8 or 10 during this test. The clock

Clock Input

VIHmax

input is the waveform shown.

6. In addition to meeting the output levels specified, the device must divide by 6, 9 or 11 during this test. The clock input is the waveform shown.

SWITCHING CHARACTERISTICS

		Pin			MC	12009, N	NC1201	1, MC12	013			TEST VOLTAGES/WAVEFORMS APPLIED TO PINS LISTED BELOW:								BELOW:
		Under		-30°C	-		+25°C	-		+85°C	-		Pulse	Pulse	Pulse	VIHmin	VILmin	VF	VEE	Vcc
Characteristic	Symbol	Test	Min	Тур	Max	Min	Тур	Max	Min	Тур	Max	Unit	Gen.1	Gen.2	Gen.3	t	†	-3.0 V	-3.0 V	+2.0
Propagation Delay (See Figures 3 and 5)	t _{15+ 2+} t _{15+ 2-} t _{5+ 7+} t _{5- 7-}	2 2 7 7			8.1 7.5 8.4 6.5			8.1 7.5 8.1 6.5			8.9 8 2 8.9 7.1	ns ↓	15 15 A A				11,12,13 11,12,13 — —	9,10 9,10 — —	8 8 8	1,6,16 1,6,16 1,6,16 1,6,16
Setup Time (See Figures 4 and 5)	t _{setup1} t _{setup2}	11 9	5.0 5.0	_		5.0 5.0	_		5.0 5.0	_		ns ns	15 15	· _	*		* 11,12,13	9,10 *	8 8	1,6,16 1,6,16
Release Time (See Figures 4 and 5)	t _{rel1} t _{rel2}	11 9	5.0 5.0	-		5.0 5.0	_		5.0 5.0	-		ns ns	15 15	· _	*		* 11,12,13	9.10 *	8 8	1,6,16 1,6,16
Toggle Frequency (See Figure 6) MC12009 : 5/6 MC12011 : 8/9 MC12013 : 10/11	f _{max}	2	440 500 500			480 550 550			440 500 500			MHz				11 11 11			8 8 8	16 16 16

*Test inputs sequentially, with Pulse Generator 2 or 3 as indicated connected to input under test, and the voltage indicated applied to the other input(s) of the same type (i.e., MECL or MTTL).

	-30°C	+ 25°C	+ 85°C	
†V _{IHmin}	+ 1.03	+ 1.115	+ 1.20	Vdc
†V _{ILmin}	+ 0.175	+ 0.200	+ 0.235	Vdc

Figure 3. AC Voltage Waveforms



Figure 4. Setup and Release Time Waveforms



Figure 5. AC Test Circuit



Figure 6. Maximum Frequency Test Circuit



Unused output connected to a 50 Ω resistor to ground



DIVIDE BY 9







Figure 7. State Diagram

DIVIDE BY 5/6 (MC12009/MC12509)



The State of the Enable is important <u>only</u> for the positive Clock Transition when the counter is in state 1100.

1111

MC12009 MC12011 MC12013 APPLICATIONS INFORMATION

The primary application of these devices is as a high–speed variable modulus prescaler in the divide by N section of a phase–locked loop synthesizer used as the local oscillator of two–way radios.

Proper VHF termination techniques should be followed when the clock is separated from the prescaler by any appreciable distance.

In their basic form, these devices will divide by 5/6, 8/9, or 10/11. Division by 5, 8, or 10 occurs when any one or all

of the five gate inputs E1 through E5 are high. Division by 6, 9, or 11 occurs when all inputs E1 through E5 are low. (Unconnected MTTL inputs are normally high, unconnected MECL inputs are normally low). With the addition of extra parts, many different division configurations may be obtained (20/21, 40/41, 50/51, 100/101, etc.) A few of the many configurations are shown below, only for the MC12013.



Q1 Q2 Q3 Q4 Enable = 0 Enable = 1

Figure 8. Divide By 10/11 (MC12013)

Figure 9. Divide By 20/21 (MC12013)



	COUNT	Q1	Q2	Q3	Q4	Q4	
	31	1	1	1	1	1	
	30	0	1	1	1	1	
	28	0	0	1	1	1	
	24	24 0 0 0 1 1	1				
	25	1	0	0	1	1	
	27	1	1	0	1	1	
	22	0	1	1	0	1	
	20	0	0	1	0	1	
	16	0	0	0	0	1	
	17	1	0	0	0	1	
E2 + E3 + E4 + E5 = 0	19	1	1	0	0	1	E2 + E3 + E4 + E5 = 1
	14	0	1	1	1	0	
	12	0	0	1	1	0	
	8	0	0	0	1	0	
	9	1	0	0	1	0	
	11	1	1	0	1	0	
	6	0	1	1	0	0	
	4	0	0	1	0	0	
	0	0	0	0	0 0		
	1	1	0	0	0	0	
	3	1	1	0	0	0	

To obtain an MTTL output, connect Pins 5 and 4 to Pins 2 and 3 respectively. Termination resistors for the MECL outputs are not shown, but are required except for the flip–flop driving the translator section.

The \div 20/21 counter may also be built using an MTTL flip–flop by connecting Pins 5 and 4 to Pins 2 and 3 respectively, and driving the MTTL flip–flop with Pin 7. MC12013 inputs E4 and E5 are used rather than E1. With E1 + E2 + E3 = 0, operation remains as shown.

Figure 10. Divide By 40/41 (MC12013)



For $\div 40$: E4 + E5 = 1 For $\div 41$: E4 + E5 = 0

Termination resistors for MECL outputs are not shown, but are required except for the flip–flop driving the translator section.

OUTLINE DIMENSIONS



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